## TLC27L4, 運送第27世4内/ 再担係27L4日/ / 「用比の多7上年Y, TLC27L9 LinCMOS™ PRECISION QUAD OPERATIONAL AMPLIFIERS

SLOS053C - OCTOBER 1987 - REVISED AUGUST 1994

Trimmed Offset Voltage:

TLC27L9 . . . 900  $\mu$ V Max at 25°C,  $V_{DD} = 5 \text{ V}$ 

- Input Offset Voltage Drift . . . Typically
   0.1 μV/Month, Including the First 30 Days
- Wide Range of Supply Voltages Over Specified Temperature Range:

0°C to 70°C . . . 3 V to 16 V -40°C to 85°C . . . 4 V to 16 V -55°C to 125°C . . . 4 V to 16 V

- Single-Supply Operation
- Common-Mode Input Voltage Range Extends Below the Negative Rail (C-Suffix, I-Suffix Types)
- Ultra-Low Power . . . Typically 195 μW at 25°C, V<sub>DD</sub> = 5 V
- Output Voltage Range includes Negative Rail
- High Input Impedance . . . 10<sup>12</sup> Ω Typ
- ESD-Protection Circuitry
- Small-Outline Package Option Also Available in Tape and Reel
- Designed-In Latch-Up Immunity

#### description

The TLC27L4 and TLC27L9 quad operational amplifiers combine a wide range of input offset voltage grades with low offset voltage drift, high input impedance, extremely low power, and high gain.

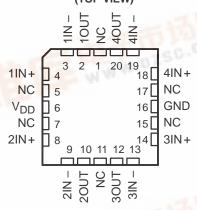
These devices use Texas instruments silicon-gate LinCMOS™ technology, which provides offset voltage stability far exceeding the stability available with conventional metal-gate processes.

The extremely high input impedance, low bias currents, and low-power consumption make these cost-effective devices ideal for high-gain, low- frequency, low-power applications. Four offset voltage grades are available (C-suffix and l-suffix types), ranging from the low-cost TLC27L4 (10 mV) to the high-precision TLC27L9 (900  $\mu$ V). These advantages, in combination with good common-mode rejection and supply voltage rejection, make these devices a good choice for new state-of-the-art designs as well as for upgrading existing designs.

## D, J, N, OR PW PACKAGE (TOP VIEW)

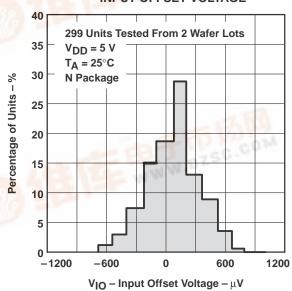


#### FK PACKAGE (TOP VIEW)



NC - No internal connection

## DISTRIBUTION OF TLC27L9 INPUT OFFSET VOLTAGE



SLOS053C - OCTOBER 1987 - REVISED AUGUST 1994

#### description (continued)

In general, many features associated with bipolar technology are available on LinCMOS™ operational amplifiers, without the power penalties of bipolar technology. General applications such as transducer interfacing, analog calculations, amplifier blocks, active filters, and signal buffering are easily designed with the TLC27L4 and TLC27L9. The devices also exhibit low voltage single-supply operation and ultra-low power consumption, making them ideally suited for remote and inaccessible battery-powered applications. The common-mode input voltage range includes the negative rail.

A wide range of packaging options is available, including small-outline and chip-carrier versions for high-density system applications.

The device inputs and outputs are designed to withstand –100-mA surge currents without sustaining latch-up.

The TLC27L4 and TLC27L9 incorporate internal ESD-protection circuits that prevent functional failures at voltages up to 2000 V as tested under MIL-STD-883C, Method 3015.2; however, care should be exercised in handling these devices, as exposure to ESD may result in the degradation of the device parametric performance.

The C-suffix devices are characterized for operation from  $0^{\circ}$ C to  $70^{\circ}$ C. The I-suffix devices are characterized for operation from  $-40^{\circ}$ C to  $85^{\circ}$ C. The M-suffix devices are characterized for operation from  $-55^{\circ}$ C to  $125^{\circ}$ C.

#### **AVAILABLE OPTIONS**

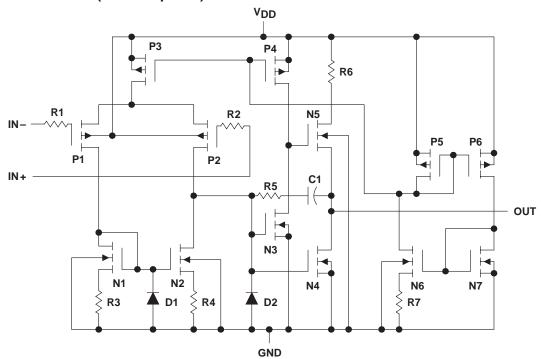
			PA	CKAGED DEVIC	ES		CHIP
TA	V <sub>IO</sub> max AT 25°C	SMALL OUTLINE (D)	CHIP CARRIER (FK)	CERAMIC DIP (J)	PLASTIC DIP (N)	TSSOP (PW)	FORM (Y)
	900 μV	TLC27L9CD	_	_	TLC27L9CN	_	_
0°C to 70°C	2 mV	TLC27L4BCD	_	_	TLC27L4BCN	_	_
0 0 10 70 0	5 mV	TLC27L4ACD	_	_	TLC27L4ACN	_	_
	10 mV	TLC27L4CD	_	_	TLC27L4CN	TLC27L4CPW	TLC27L4Y
	900 μV	TLC27L9ID	_	_	TLC27L9IN	_	_
-40°C to 85°C	2 mV	TLC27L4BID	_	_	TLC27L4BIN	_	_
-40 C to 65 C	5 mV	TLC27L4AID	_	_	TLC27L4AIN	_	_
	10 mV	TLC27L4ID	_	_	TLC27L4IN	_	_
-55°C to 125°C	900 μV	TLC27L9MD	TLC27L9MFK	TLC27L9MJ	TLC27L9MN	_	_
-33 C to 123 C	10 mV	TLC27L4MD	TLC27L4MFK	TLC27L4MJ	TLC27L4MN	_	_

The D package is available taped and reeled. Add R suffix to the device type (e.g., TLC27L9CDR).



SLOS053C - OCTOBER 1987 - REVISED AUGUST 1994

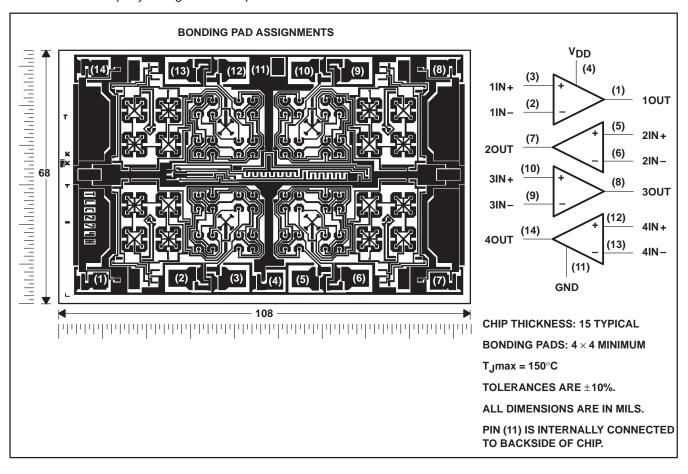
### equivalent schematic (each amplifier)



SLOS053C - OCTOBER 1987 - REVISED AUGUST 1994

#### TLC27L4Y chip information

These chips, when properly assembled, display characteristics similar to the TLC27L4C. Thermal compression or ultrasonic bonding may be used on the doped-aluminum bonding pads. Chips may be mounted with conductive epoxy or a gold-silicon preform.



SLOS053C - OCTOBER 1987 - REVISED AUGUST 1994

#### absolute maximum ratings over operating free-air temperature (unless otherwise noted)†

Differential input voltage, V <sub>ID</sub> (see Non- Input voltage range, V <sub>I</sub> (any input)	Note 2)	±V <sub>DD</sub> 0.3 V to V <sub>DD</sub>
Total current into V <sub>DD</sub>		45 mA
Duration of short-circuit current at (c	or below) 25°C (see Note 3)	unlimited
Continuous total dissipation		See Dissipation Rating Table
Operating free-air temperature, T <sub>A</sub> :	C suffix	0°C to 70°C
	I suffix	40°C to 85°C
	M suffix	–55°C to 125°C
Storage temperature range		–65°C to 150°C
	FK package	
Lead temperature 1,6 mm (1/16 incl	h) from case for 10 seconds: D, N, or PW pa	ackage 260°C
Lead temperature 1,6 mm (1/16 incl		

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltage values, except differential voltages, are with respect to network ground.

- 2. Differential voltages are at IN+ with respect to IN-.
- 3. The output may be shorted to either supply. Temperature and/or supply voltages must be limited to ensure that the maximum dissipation rating is not exceeded (see application section).

#### **DISSIPATION RATING TABLE**

PACKAGE	$T_{\mbox{A}} \leq 25^{\circ}\mbox{C}$ POWER RATING	DERATING FACTOR ABOVE T <sub>A</sub> = 25°C	T <sub>A</sub> = 70°C POWER RATING	T <sub>A</sub> = 85°C POWER RATING	T <sub>A</sub> = 125°C POWER RATING
D	950 mW	7.6 mW/°C	608 mW	494 mW	_
FK	1375 mW	11.0 mW/°C	880 mW	715 mW	275 mW
J	1375 mW	11.0 mW/°C	880 mW	715 mW	275 mW
N	1575 mW	12.6 mW/°C	1008 mW	819 mW	_
PW	700 mW	5.6 mW/°C	448 mW	_	_

### recommended operating conditions

		C SU	FFIX	I SUF	FIX	M SU	FFIX	UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	UNIT
Supply voltage, V <sub>DD</sub>		3	16	4	16	4	16	V
Common-mode input voltage, V <sub>IC</sub>	V <sub>DD</sub> = 5 V	-0.2	3.5	-0.2	3.5	0	3.5	V
Common-mode input voitage, v <sub>IC</sub>	V <sub>DD</sub> = 10 V	-0.2	8.5	-0.2	8.5	0	8.5	V
Operating free-air temperature, TA		0	70	-40	85	-55	125	°C



SLOS053C - OCTOBER 1987 - REVISED AUGUST 1994

## electrical characteristics at specified free-air temperature, $V_{DD}$ = 5 V (unless otherwise noted)

	PARAMETER		TEST CONI	DITIONS	T <sub>A</sub> †	TLC27L4C TLC27L4AC TLC27L4BC TLC27L9C			UNIT
						MIN	TYP	MAX	
		TLC27L4C	V <sub>O</sub> = 1.4 V,	V <sub>IC</sub> = 0,	25°C		1.1	10	
		TLC27L4C	$R_S = 50 \Omega$ ,	$R_L = 1 M\Omega$	Full range			12	mV
		TLC27L4AC	V <sub>O</sub> = 1.4 V,	$V_{IC} = 0$ ,	25°C		0.9	5	l ''' v
VIO	Input offset voltage	TEG27E4AC	$R_S = 50 \Omega$ ,	$R_L = 1 M\Omega$	Full range			6.5	
۷IO	input onset voltage	TLC27L4BC	$V_0 = 1.4 V$ ,	$V_{IC} = 0$ ,	25°C		240	2000	
		TEG27E4BC	$R_S = 50 \Omega$ ,	$R_L = 1 M\Omega$	Full range			3000	μV
		TLC27L9C	$V_0 = 1.4 V$	$V_{IC} = 0$ ,	25°C		200	900	μν
		11027190	$R_S = 50 \Omega$ ,	$R_L = 1 M\Omega$	Full range			1500	
αVIO	Average temperature co offset voltage	efficient of input			25°C to 70°C		1.1		μV/°C
		N ( 1)	V 0.5.V	.,	25°C		0.1		
IO	Input offset current (see	Note 4)	$V_0 = 2.5 V$ ,	$V_{IC} = 2.5 V$	70°C		7	300	pΑ
					25°C		0.6		
ΙΒ	Input bias current (see N	lote 4)	$V_0 = 2.5 V$ ,	$V_{IC} = 2.5 V$	70°C		40	600	pА
.,	Common mode input vo	Itage range			25°C	-0.2 to 4	-0.3 to 4.2		V
VICR	(see Note 5)				Full range	-0.2 to 3.5			V
					25°C	3.2	4.1		
Vон	High-level output voltage	e	$V_{ID} = 100 \text{ mV},$	$R_L = 1 M\Omega$	0°C	3	4.1		V
					70°C	3	4.2		1
					25°C		0	50	
$V_{OL}$	Low-level output voltage		$V_{ID} = -100 \text{ mV},$	$I_{OL} = 0$	0°C		0	50	mV
					70°C		0	50	1
					25°C	50	520		
AVD	Large-signal differential amplification	voltage	$V_0 = 2.5 \text{ V to 2 V},$	$R_L = 1 M\Omega$	0°C	50	680		V/mV
	анірінісацоп				70°C	50	380		
					25°C	65	94		
CMRR	Common-mode rejection	n ratio	V <sub>IC</sub> = V <sub>ICR</sub> min		0°C	60	95		dB
					70°C	60	95		
					25°C	70	97		
ksvr	Supply-voltage rejection	ratio	$V_{DD} = 5 \text{ V to } 10 \text{ V},$	V <sub>O</sub> = 1.4 V	0°C	60	97		dB
	$(\Delta V_{DD}/\Delta V_{IO})$				70°C	60	98		
	-				25°C		40	68	
$I_{DD}$	Supply current (four amp	olifiers)	V <sub>O</sub> = 2.5 V, No load	$V_{IC} = 2.5 V,$	0°C		48	84	μΑ
- <b>-</b>		•	INO IDAU		70°C		31	56	l .

<sup>†</sup>Full range is 0°C to 70°C.

NOTES: 4. The typical values of input bias current and input offset current below 5 pA were determined mathematically.



SLOS053C - OCTOBER 1987 - REVISED AUGUST 1994

## electrical characteristics at specified free-air temperature, $V_{\mbox{\scriptsize DD}}$ = 10 V (unless otherwise noted)

	PARAMETER		TEST CON	DITIONS	T <sub>A</sub> †	TL TL	.C27L40 .C27L4 <i>A</i> .C27L4E .C27L90	C SC	UNIT
						MIN	TYP	MAX	
		TLC27L4C	V <sub>O</sub> = 1.4 V,	V <sub>IC</sub> = 0,	25°C		1.1	10	
		12027240	$R_S = 50 \Omega$ ,	$R_L = 1 M\Omega$	Full range			12	mV
		TLC27L4AC	V <sub>O</sub> = 1.4 V,	V <sub>IC</sub> = 0,	25°C		0.9	5	IIIV
V <sub>IO</sub>	Input offset voltage	TEOZTEAAC	$R_S = 50 \Omega$ ,	$R_L = 1 M\Omega$	Full range			6.5	
100	input onset voltage	TLC27L4BC	$V_0 = 1.4 V$ ,	$V_{IC} = 0$ ,	25°C		260	2000	
		120272480	$R_S = 50 \Omega$ ,	$R_L = 1 M\Omega$	Full range			3000	μV
		TLC27L9C	$V_0 = 1.4 V$ ,	$V_{IC} = 0$ ,	25°C		210	1200	μν
		112027230	$R_S = 50 \Omega$ ,	$R_L = 1 M\Omega$	Full range			1900	
ανιο	Average temperature coe input offset voltage	efficient of			25°C to 70°C		1		μV/°C
1	Innuit offeet ourrent (e.e.	Note 4)	V- 5 V	\/.a	25°C		0.1		- A
lio	Input offset current (see	Note 4)	$V_0 = 5 V$ ,	$V_{IC} = 5 V$	70°C		7	300	pА
L-	lanut bigg gurrent (a.c. N	oto 4)	V - F V	\/ E\/	25°C		0.7		- A
IB	Input bias current (see N	ote 4)	$V_0 = 5 V$ ,	$V_{IC} = 5 V$	70°C		50	600	pА
.,	Common-mode input vol	tage range			25°C	-0.2 to 9	-0.3 to 9.2		V
VICR	(see Note 5)	0 0			Full range	-0.2 to 8.5			V
					25°C	8	8.9		
Vон	High-level output voltage		$V_{ID} = 100 \text{ mV},$	$R_L = 1 M\Omega$	0°C	7.8	8.9		V
					70°C	7.8	8.9		
					25°C		0	50	
VOL	Low-level output voltage		$V_{ID} = -100 \text{ mV},$	$I_{OL} = 0$	0°C		0	50	mV
					70°C		0	50	
					25°C	50	870		
AVD	Large-signal differential vamplification	oltage	$V_0 = 1 V to 6 V$ ,	$R_L = 1 M\Omega$	0°C	50	1020		V/mV
	атриновного				70°C	50	660		
					25°C	65	97		
CMRR	Common-mode rejection	ratio	V <sub>IC</sub> = V <sub>ICR</sub> min		0°C	60	97		dB
					70°C	60	97		
	Complements of the state of				25°C	70	97		
ksvr	Supply-voltage rejection (ΔV <sub>DD</sub> /ΔV <sub>IO</sub> )	ratio	$V_{DD} = 5 \text{ V to } 10 \text{ V},$	$V_0 = 1.4 \text{ V}$	0°C	60	97		dB
					70°C	60	98		
				V 5.V	25°C		57	92	
I <sub>DD</sub>	Supply current (four amp	lifiers)	V <sub>O</sub> = 5 V, No load	$V_{IC} = 5 V$ ,	0°C		72	132	μΑ
					70°C		44	80	

† Full range is 0°C to 70°C.

NOTES: 4. The typical values of input bias current and input offset current below 5 pA were determined mathematically.



SLOS053C - OCTOBER 1987 - REVISED AUGUST 1994

### electrical characteristics at specified free-air temperature, $V_{DD} = 5 \text{ V}$ (unless otherwise noted)

	PARAMETER		TEST CONI	DITIONS	T <sub>A</sub> †	TL TL	.C27L4I .C27L4 <i>I</i> .C27L4 <i>I</i> .C27L9I	AI BI	UNIT
						MIN	TYP	MAX	
		TLC27L4I	V <sub>O</sub> = 1.4 V,	V <sub>IC</sub> = 0,	25°C		1.1	10	
		11.02/141	$R_S = 50 \Omega$ ,	$R_L = 1 M\Omega$	Full range			13	mV
		TLC27L4AI	V <sub>O</sub> = 1.4 V,	V <sub>IC</sub> = 0,	25°C		0.9	5	mv
\/.o	Input offset voltage	TLG27L4AI	$R_S = 50 \Omega$ ,	$R_L = 1 M\Omega$	Full range			7	
VIO	input onset voltage	TLC27L4BI	V <sub>O</sub> = 1.4 V,	$V_{IC} = 0$ ,	25°C		240	2000	
		TLO27L4BI	$R_S = 50 \Omega$ ,	$R_L = 1 M\Omega$	Full range			3500	μV
		TLC27L9I	V <sub>O</sub> = 1.4 V,	V <sub>IC</sub> = 0,	25°C		200	900	μν
		11027191	$R_S = 50 \Omega$ ,	$R_L = 1 M\Omega$	Full range			2000	
αVIO	Average temperature co	efficient of input			25°C to 85°C		1.1		μV/°C
	1	N. ( A)	V 0.5.V	.,	25°C		0.1		
IIO	Input offset current (see	Note 4)	$V_0 = 2.5 V$ ,	$V_{IC} = 2.5 V$	85°C		24	1000	pΑ
			.,	.,	25°C		0.6		
ΙΒ	Input bias current (see I	Note 4)	V <sub>O</sub> = 2.5 V,	$V_{IC} = 2.5 V$	85°C		200	2000	pА
.,	Common-mode input vo	oltage range			25°C	-0.2 to 4	-0.3 to 4.2		V
VICR	(see Note 5)	ŭ ŭ			Full range	-0.2 to 3.5			V
					25°C	3.2	4.1		
Vон	High-level output voltag	е	$V_{ID} = 100 \text{ mV},$	$R_L = 1 M\Omega$	-40°C	3	4.1		V
					85°C	3	4.2		
					25°C		0	50	
$V_{OL}$	Low-level output voltage	e	$V_{ID} = -100 \text{ mV},$	$I_{OL} = 0$	-40°C		0	50	mV
					85°C		0	50	
					25°C	50	480		
AVD	Large-signal differential amplification	voltage	$V_0 = 0.25 \text{ V to 2 V},$	$R_L = 1 M\Omega$	-40°C	50	900		V/mV
	απριποαιίστ				85°C	50	330		
					25°C	65	94		
CMRR	Common-mode rejectio	n ratio	V <sub>IC</sub> = V <sub>ICR</sub> min		-40°C	60	95		dB
					85°C	60	95		
					25°C	70	97		
ksvr	Supply-voltage rejection (ΔVDD/ΔVIO)	ratio	$V_{DD} = 5 \text{ V to } 10 \text{ V},$	$V_0 = 1.4 \text{ V}$	-40°C	60	97		dB
	(7 A DD / 7 A IQ)				85°C	60	98		
			0.534	.,	25°C		39	68	
$I_{DD}$	Supply current (four am	plifiers)	V <sub>O</sub> = 2.5 V, No load	$V_{IC} = 2.5 V,$	-40°C		62	108	μΑ
			1.15 1000		85°C		29	52	

<sup>†</sup>Full range is -40°C to 85°C.

NOTES: 4. The typical values of input bias current and input offset current below 5 pA were determined mathematically.



SLOS053C - OCTOBER 1987 - REVISED AUGUST 1994

## electrical characteristics at specified free-air temperature, $V_{DD}$ = 10 V (unless otherwise noted)

	PARAMETER		TEST CONI	DITIONS	τ <sub>Α</sub> †	TL TL	.C27L4I .C27L4 <i>I</i> .C27L4E .C27L9I	AI BI	UNIT
						MIN	TYP	MAX	
		TLC27L4I	$V_0 = 1.4 V$	$V_{IC} = 0$ ,	25°C		1.1	10	
			$R_S = 50 \Omega$ ,	$R_L = 1 M\Omega$	Full range			13	mV
		TLC27L4AI	$V_0 = 1.4 \text{ V},$	$V_{IC} = 0$ ,	25°C		0.9	5	
VIO	Input offset voltage		$R_S = 50 \Omega$ ,	$R_L = 1 M\Omega$	Full range			7	
		TLC27L4BI	$V_0 = 1.4 \text{ V},$	$V_{IC} = 0$ ,	25°C		260	2000	
			$R_S = 50 \Omega$ ,	$R_L = 1 M\Omega$	Full range			3500	μV
		TLC27L9I	$V_0 = 1.4 \text{ V},$	$V_{IC} = 0$ ,	25°C		210	1200	μ.
			$R_S = 50 \Omega$ ,	$R_L = 1 M\Omega$	Full range			2900	
ανιο	Average temperature coeffset voltage	ficient of input			25°C to 85°C		1		μV/°C
li a	Input offset current (see N	loto 4)	V- 5.V	V <sub>IC</sub> = 5 V	25°C		0.1		~ ^
10	input onset current (see N	iote 4)	V <sub>O</sub> = 5 V,	AIC = 2 A	85°C		26	1000	pА
1	Innuit high gurrant (ago Na	to 4\	V - 5 V	V E.V.	25°C		0.7		~ ^
lΒ	Input bias current (see No	ite 4)	$V_0 = 5 V$ ,	$V_{IC} = .5 V$	85°C		220	2000	pА
	Common-mode input volta	ago rongo			25°C	-0.2 to 9	-0.3 to 9.2		V
VICR	(see Note 5)	age range			Full range	-0.2 to 8.5			V
					25°C	8	8.9		
∨он	High-level output voltage		$V_{ID} = 100 \text{ mV},$	$R_L = 1 M\Omega$	-40°C	7.8	8.9		V
					85°C	7.8	8.9		
					25°C		0	50	
VOL	Low-level output voltage		$V_{ID} = -100 \text{ mV},$	$I_{OL} = 0$	-40°C		0	50	mV
					85°C		0	50	
					25°C	50	800		
AVD	Large-signal differential vo amplification	oltage	$V_0 = 1 \text{ V to 6 V},$	$R_L = 1 M\Omega$	-40°C	50	1550		V/mV
	ampilioation				85°C	50	585		
					25°C	65	97		
CMRR	Common-mode rejection	atio	V <sub>IC</sub> = V <sub>ICR</sub> min		-40°C	60	97		dB
					85°C	60	98		
					25°C	70	97		
ksvr	Supply-voltage rejection ra (ΔV <sub>DD</sub> /ΔV <sub>IO</sub> )	atio	$V_{DD} = 5 \text{ V to } 10 \text{ V},$	$V_0 = 1.4 \text{ V}$	-40°C	60	97		dB
	יטטי≏יוט <i>ו</i>				85°C	60	98		
					25°C		57	92	
I <sub>DD</sub>	Supply current (four ampli	fiers)	V <sub>O</sub> = 5 V, No load	$V_{IC} = 5 V$	-40°C		98	172	μΑ
			1.101000		85°C		40	72	

†Full range is -40°C to 85°C.

NOTES: 4. The typical values of input bias current and input offset current below 5 pA were determined mathematically.



SLOS053C - OCTOBER 1987 - REVISED AUGUST 1994

## electrical characteristics at specified free-air temperature, $V_{DD} = 5 \text{ V}$ (unless otherwise noted)

	PARAMETER		TEST CONI	DITIONS	T <sub>A</sub> †		.C27L4N .C27L9N		UNIT
						MIN	TYP	MAX	
		TLC27L4M	V <sub>O</sub> = 1.4 V,	V <sub>IC</sub> = 0,	25°C		1.1	10	mV
\/.a	Input offeet voltage	TLC2/L4IVI	$R_S = 50 \Omega$ ,	$R_L = 1 M\Omega$	Full range			12	IIIV
VIO	Input offset voltage	TLC27L9M	V <sub>O</sub> = 1.4 V,	V <sub>IC</sub> = 0,	25°C		200	900	μV
		TLG27L9W	$R_S = 50 \Omega$ ,	$R_L = 1 M\Omega$	Full range			3750	μν
αVIO	Average temperature coeff offset voltage	icient of input			25°C to 125°C		1.4		μV/°C
lio.	Input offset current (see No	oto 4)	V <sub>O</sub> = 2.5 V,	V <sub>IC</sub> = 2.5 V	25°C		0.1		pА
110	input onset current (see No	Jie 4)	V() = 2.5 V,	VIC = 2.5 V	125°C		1.4	15	nA
1.5	Input bigg ourrent (age Not	·o. 4)	V <sub>O</sub> = 2.5 V,	V <sub>IC</sub> = 2.5 V	25°C		0.6		pA
ΙΙΒ	Input bias current (see Not	.e 4)	VO = 2.5 V,	AIC = 5.2 A	125°C		9	35	nA
\\.	Common-mode input volta	ge range			25°C	-0.2 to 4	-0.3 to 4.2		٧
VICR	(see Note 5)				Full range	-0.2 to 3.5			٧
					25°C	3.2	4.1		
Vон	High-level output voltage		$V_{ID} = 100 \text{ mV},$	$R_L = 1 M\Omega$	−55°C	3	4.1		V
					125°C	3	4.2		
					25°C		0	50	
VOL	Low-level output voltage		$V_{ID} = -100 \text{ mV},$	IOL = 0	−55°C		0	50	mV
					125°C		0	50	
					25°C	50	480		
AVD	Large-signal differential vo amplification	itage	$V_0 = 0.25 \text{ V to 2 V},$	$R_L = 1 M\Omega$	−55°C	25	950		V/mV
					125°C	25	200		
					25°C	65	94		
CMRR	Common-mode rejection ra	atio	V <sub>IC</sub> = V <sub>ICR</sub> min		−55°C	60	95		dB
					125°C	60	85		
	0 1 1 1 1 1				25°C	70	97		
ksvr	Supply-voltage rejection ra (ΔV <sub>DD</sub> /ΔV <sub>IO</sub> )	OITIO	$V_{DD} = 5 V \text{ to } 10 V,$	$V_0 = 1.4 \ V$	−55°C	60	97		dB
	( 'Ul' 'Ul'				125°C	60	98		
			V 0.517	.,	25°C		39	68	
$I_{DD}$	Supply current (four amplif	iers)	V <sub>O</sub> = 2.5 V, No load	VIC = 2.5 V,	−55°C		69	120	μΑ
					125°C		27	48	

† Full range is -55°C to 125°C.

NOTES: 4. The typical values of input bias current and input offset current below 5 pA were determined mathematically.

SLOS053C - OCTOBER 1987 - REVISED AUGUST 1994

## electrical characteristics at specified free-air temperature, $V_{\mbox{\scriptsize DD}}$ = 10 V (unless otherwise noted)

	PARAMETER		TEST CON	DITIONS	T <sub>A</sub> †		.C27L4N .C27L9N		UNIT
						MIN	TYP	MAX	
		TLC27L4M	V <sub>O</sub> = 1.4 V,	V <sub>IC</sub> = 0,	25°C		1.1	10	\/
\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	lanut offeet voltage	1LC2/L4IVI	$R_S = 50 \Omega$ ,	$R_L = 1 M\Omega$	Full range			12	mV
VIO	Input offset voltage	TLC27L9M	V <sub>O</sub> = 1.4 V,	V <sub>IC</sub> = 0,	25°C		210	1200	/
		TLG27L9W	$R_S = 50 \Omega$ ,	$R_L = 1 M\Omega$	Full range			4300	μV
ανιο	Average temperature coeffinput offset voltage	ficient of			25°C to 125°C		1.4		μV/°C
1	Innut offeet ourrent (e.g. h	loto 4)	V- 5V	\/ E\/	25°C		0.1		рА
lio	Input offset current (see N	lote 4)	$V_0 = 5 V$ ,	$V_{IC} = 5 V$	125°C		1.8	15	nA
	Input him ourrent (one No	to 4)	V- 5 V	\/.a	25°C		0.7		рΑ
IB	Input bias current (see No	te 4)	$V_0 = 5 V$ ,	$V_{IC} = 5 V$	125°C		10	35	nA
VICR	Common-mode input volta	age range			25°C	0 to 9	-0.3 to 9.2		V
VICR	(see Note 5)				Full range	0 to 8.5			V
					25°C	8	8.9		
Vон	High-level output voltage		$V_{ID} = 100 \text{ mV},$	$R_L = 1 M\Omega$	−55°C	7.8	8.8		V
					125°C	7.8	9		
					25°C		0	50	
VOL	Low-level output voltage		$V_{ID} = -100 \text{ mV},$	$I_{OL} = 0$	−55°C		0	50	mV
					125°C		0	50	
	Lanca d'acatal estaca d'alors	- U =			25°C	50	800		
AVD	Large-signal differential vo amplification	oitage	$V_0 = 1 \text{ V to 6 V},$	$R_L = 1 M\Omega$	−55°C	25	1750		V/mV
					125°C	25	380		
					25°C	65	97		
CMRR	Common-mode rejection	atio	V <sub>IC</sub> = V <sub>ICR</sub> min		−55°C	60	97		dB
					125°C	60	91		
	Owner by condition and the office of	- 11 -			25°C	70	97		
ksvr	Supply-voltage rejection ra (ΔV <sub>DD</sub> /ΔV <sub>IO</sub> )	atio	$V_{DD} = 5 \text{ V to } 10 \text{ V},$	$V_0 = 1.4 \ V$	−55°C	60	97		dB
					125°C	60	98		
					25°C		57	92	
I <sub>DD</sub>	Supply current (four ampli	fiers)	V <sub>O</sub> = 5 V, No load	$V_{IC} = 5 V$	−55°C		111	192	μΑ
					125°C		35	60	

<sup>†</sup>Full range is -55°C to 125°C.

NOTES: 4. The typical values of input bias current and Input offset current below 5 pA were determined mathematically.

SLOS053C - OCTOBER 1987 - REVISED AUGUST 1994

## electrical characteristics at specified free-air temperature, $V_{DD}$ = 5 V, $T_A$ = 25°C (unless otherwise noted)

	PARAMETER	TEST CONI	OITIONE	Τι	_C27L4\	′	UNIT
	PARAMETER	TEST CONI	DITIONS	MIN	TYP	MAX	UNIT
V <sub>IO</sub>	Input offset voltage	$V_{O} = 1.4 \text{ V},$ $R_{S} = 50 \Omega,$	$V_{IC} = 0,$ $R_L = 1 M\Omega$		1.1	10	mV
ανιο	Average temperature coefficient of input offset voltage	$T_A = 25^{\circ}C$ to $70^{\circ}C$			1.1		μV/°C
IIO	Input offset current (see Note 4)	V <sub>O</sub> = 2.5 V,	V <sub>IC</sub> = 2.5 V		0.1		pA
I <sub>IB</sub>	Input bias current (see Note 4)	V <sub>O</sub> = 2.5 V,	V <sub>IC</sub> = 2.5 V		0.6		pA
VICR	Common-mode input voltage range (see Note 5)			-0.2 to 4	-0.3 to 4.2		٧
Vон	High-level output voltage	V <sub>ID</sub> = 100 mV,	$R_L = 1 M\Omega$	3.2	4.1		V
VOL	Low-level output voltage	$V_{ID} = -100 \text{ mV},$	I <sub>OL</sub> = 0		0	50	mV
AVD	Large-signal differential voltage amplification	$V_0 = 0.25 \text{ V to 2 V},$	$R_L = 1 M\Omega$	50	520		V/mV
CMRR	Common-mode rejection ratio	V <sub>IC</sub> = V <sub>ICR</sub> min		65	94		dB
ksvr	Supply-voltage rejection ratio (ΔV <sub>DD</sub> /ΔV <sub>IO</sub> )	$V_{DD} = 5 \text{ V to } 10 \text{ V},$	V <sub>O</sub> = 1.4 V	70	97		dB
I <sub>DD</sub>	Supply current (four amplifiers)	V <sub>O</sub> = 2.5 V, No load	V <sub>IC</sub> = 2.5 V,		40	68	μА

## electrical characteristics at specified free-air temperature, $V_{DD}$ = 10 V, $T_A$ = 25°C (unless otherwise noted)

	PARAMETER	TEST CONI	OITIONS	TI	C27L4Y	′	UNIT
	FARAMETER	TEST CONL	DITIONS	MIN	TYP	MAX	UNIT
V <sub>IO</sub>	Input offset voltage	$V_{O} = 1.4 \text{ V},$ RS = 50 $\Omega$ ,	$V_{IC} = 0,$ $R_L = 1 M\Omega$		1.1	10	mV
αγιο	Average temperature coefficient of input offset voltage	$T_A = 25^{\circ}C$ to $70^{\circ}C$			1		μV/°C
IIO	Input offset current (see Note 4)	V <sub>O</sub> = 5 V,	$V_{IC} = 5 V$		0.1		рА
I <sub>IB</sub>	Input bias current (see Note 4)	V <sub>O</sub> = 5 V,	$V_{IC} = 5 V$		0.7		рА
VICR	Common-mode input voltage range (see Note 5)			-0.2 to 9	-0.3 to 9.2		V
Vон	High-level output voltage	$V_{ID} = 100 \text{ mV},$	$R_L = 1 M\Omega$	8	8.9		V
VOL	Low-level output voltage	$V_{ID} = -100 \text{ mV},$	I <sub>OL</sub> = 0		0	50	mV
AVD	Large-signal differential voltage amplification	$V_0 = 1 \text{ V to 6 V},$	$R_L = 1 M\Omega$	50	870		V/mV
CMRR	Common-mode rejection ratio	V <sub>IC</sub> = V <sub>ICR</sub> min		65	97		dB
ksvr	Supply-voltage rejection ratio (ΔV <sub>DD</sub> /ΔV <sub>IO</sub> )	$V_{DD} = 5 \text{ V to } 10 \text{ V},$	V <sub>O</sub> = 1.4 V	70	97		dB
I <sub>DD</sub>	Supply current (four amplifiers)	V <sub>O</sub> = 5 V, No load	V <sub>IC</sub> = 5 V,		57	92	μА

NOTES: 4. The typical values of input bias current and input offset current below 5 pA were determined mathematically.



SLOS053C - OCTOBER 1987 - REVISED AUGUST 1994

## operating characteristics at specified free-air temperature, $V_{DD} = 5 \text{ V}$

PARAMETER		TEST CONDITIONS		PARAMETER TEST CONDITIONS T <sub>A</sub>		TA	TLC27L4C TLC27L4AC TLC27L4BC TLC27L9C			UNIT				
					MIN	TYP	MAX							
				25°C		0.03								
1		R <sub>L</sub> = 1 MΩ,	V <sub>IPP</sub> = 1 V	0°C		0.04								
SR	Claus rate at units rain			70°C		0.03		1////						
J SK	Slew rate at unity gain	C <sub>L</sub> = 20 pF, See Figure 1		25°C		0.03		V/μs						
		Goo'r iguio'r		occinguic i	g		J	Cook against	$V_{IPP} = 2.5 V$	0°C		0.03		1
1				70°C		0.02		1						
Vn	Equivalent input noise voltage	f = 1 kHZ, See Figure 2	$R_S = 20 \Omega$ ,	25°C		70		nV/√ <del>Hz</del>						
			25°C		5									
ВОМ	Maximum output-swing bandwidth	$V_O = V_{OH}$ , $R_L = 1 M\Omega$ ,	C <sub>L</sub> = 20 pF, See Figure 1	0°C		6		kHz						
			See rigure r	70°C		4.5		1						
				25°C		85								
B <sub>1</sub>	Unity-gain bandwidth	V <sub>I</sub> = 10 mV, See Figure 3	$C_L = 20 pF$ ,	0°C		100		kHz						
		Joee rigure 3		70°C		65		1						
		14 40 551	( 5	25°C		34°								
φm	Phase margin			0°C		36°								
	<u> </u>	CL = 20 pr,		See rigure 3	See Figure 3	See Figure 3	See rigure 3	70°C		30°				

## operating characteristics at specified free-air temperature, $V_{DD} = 10 \text{ V}$

PARAMETER		PARAMETER TEST CONDITIONS		RAMETER TEST CONDITIONS T <sub>A</sub>		TA	TLC27L4C TLC27L4AC TLC27L4BC TLC27L9C			UNIT	
					MIN	TYP	MAX				
				25°C		0.05					
			V <sub>IPP</sub> = 1 V	0°C		0.05					
SR	Slow rate at unity gain	$R_L = 1 M\Omega$ ,		70°C		0.04		) /////			
SK	Slew rate at unity gain	C <sub>L</sub> = 20 pF, See Figure 1		25°C		0.04		V/μs			
		900 i iguio i	3			V <sub>IPP</sub> = 5.5 V	0°C		0.05		1
				70°C		0.04		1			
Vn	Equivalent input noise voltage	f = 1 kHz <sub>,</sub> See Figure 2	$R_S = 20 \Omega$ ,	25°C		70		nV/√ <del>Hz</del>			
		$V_O = V_{OH},$ $C_L = 20$ $R_I = 1 M\Omega,$ See Figu			25°C		1				
ВОМ				0°C		1.3		kHz			
			See i iguie i	70°C		0.9		1			
				25°C		110					
B <sub>1</sub>	Unity-gain bandwidth	V <sub>I</sub> = 10 mV, See Figure 3	$C_L = 20 pF$ ,	0°C		125		kHz			
		Gue i iguie 3		70°C		90		1			
		V 40 V	. 5	25°C		38°					
φm	Phase margin				0°C		40°		1		
		β_ 20 βι,	SSS Figure 5	70°C		34°		1			



SLOS053C - OCTOBER 1987 - REVISED AUGUST 1994

### operating characteristics at specified free-air temperature, $V_{DD} = 5 \text{ V}$

PARAMETER		TEST CONDITIONS		TA	TLC27L4I TLC27L4AI TLC27L4BI TLC27L9I			UNIT					
				2502	MIN	TYP	MAX						
				25°C		0.03							
			V <sub>IPP</sub> = 1 V	−40°C		0.04							
SR	Clausesta at units main	$R_L = 1 M\Omega$ ,		85°C		0.03		\//v.a					
SK	Slew rate at unity gain	C <sub>L</sub> = 20 pF, See Figure 1		25°C		0.03		V/μs					
			Ŭ	Ŭ	Ŭ			$V_{IPP} = 2.5 V$	-40°C		0.04		
				85°C		0.02							
Vn	Equivalent input noise voltage	f = 1 HZ, See Figure 2	$R_S = 20 \Omega$ ,	25°C		70		nV/√ <del>Hz</del>					
				25°C		5							
ВОМ	Maximum output-swing bandwidth		C <sub>L</sub> = 20 pF, See Figure 1	−40°C		7		kHz					
			occ rigure r	85°C		4							
						25°C		85					
В1	Unity-gain bandwidth	V <sub>I</sub> = 10 mV, See Figure 3	$C_L = 20 pF$ ,	-40°C		130		kHz					
		occ rigare 3		85°C		55							
		\\. 40 m\\	4 D	25°C		34°							
φm	Phase margin		NV, f = B <sub>1</sub> , F, See Figure 3	-40°C		38°							
		,		85°C		28°							

## operating characteristics at specified free-air temperature, $V_{DD}$ = 10 V

	PARAMETER	TEST CONDITIONS		TA	TLC27L4I TLC27L4AI TLC27L4BI TLC27L9I		UNIT								
-			1	0500	MIN	TYP	MAX								
			., .,,	25°C		0.05									
		D. 1 MO	V <sub>IPP</sub> = 1 V	-40°C		0.06									
SR	Slew rate at unity gain	$R_L = 1 M\Omega$ , $C_L = 20 pF$ ,		85°C		0.03		V/μs							
	Clow rate at unity gain	See Figure 1		25°C		0.04		ν/μο							
		Joseph			Ĭ					V <sub>IPP</sub> = 2.5 V	-40°C		0.05		
				85°C		0.03									
Vn	Equivalent input noise voltage	f = 1 HZ, See Figure 2	$R_S = 20 \Omega$ ,	25°C		70		nV/√ <del>Hz</del>							
				25°C		1									
ВОМ	Maximum output-swing bandwidth	VO = VOH,	$V_O = V_{OH},$ $C_L = 20$ $R_L = 1 M\Omega,$ See Fig.	C <sub>L</sub> = 20 pF, See Figure 1	-40°C		1.4		kHz						
		KL = 1 10152,	See Figure 1	85°C		0.8									
				25°C		110									
B <sub>1</sub>	Unity-gain bandwidth	V <sub>I</sub> = 10 mV, See Figure 3	$C_L = 20 pF$ ,	-40°C		155		kHz							
		Joce i iguie 3		85°C		80									
		14 40	( 5	25°C		38°									
φm	Phase margin	$V_{I} = 10 \text{ mV},$ $C_{L} = 20 \text{ pF},$				f = B <sub>1</sub> , See Figure 3		-40°C		42°					
	-		See Figure 3	85°C		32°									

SLOS053C - OCTOBER 1987 - REVISED AUGUST 1994

## operating characteristics at specified free-air temperature, $V_{DD} = 5 \text{ V}$

PARAMETER		ER TEST CONDITIONS		TA		LC27L4 LC27L9		UNIT						
					MIN TYP MAX  0.03  0.04  0.02  0.03  0.04  0.02		MAX							
				25°C		0.03								
			V <sub>IPP</sub> = 1 V	−55°C		0.04								
SR	Slow rate at unity gain	$R_L = 1 M\Omega$ ,		125°C		0.02	0.02	\//uc						
J SK	Slew rate at unity gain	C <sub>L</sub> = 20 pF, See Figure 1		25°C		0.03		V/μs						
		Jane 1	3	V <sub>IPP</sub> = 2.5 V	−55°C		0.04							
			125°C		0.02									
Vn	Equivalent input noise voltage	f = 1 kHz, See Figure 2	$R_S = 20 \Omega$ ,	25°C		70		nV/√ <del>Hz</del>						
				25°C		5								
ВОМ	Maximum output-swing bandwidth	$V_O = V_{OH}$ , $R_L = 1 M\Omega$ ,	$C_{O} = V_{OH}$ , $C_{L} = 20 \text{ pF}$ , $C_{L} = 1 \text{ M}\Omega$ , See Figure 1	−55°C		8		kHz						
		TC_ = 1 10152,	occ rigure r	125°C		3								
				25°C		85								
В1	Unity-gain bandwidth	V <sub>I</sub> = 10 mV, See Figure 3	$C_L = 20 pF$ ,	−55°C		140		kHz						
		Gee rigule 3		125°C		45								
		V 40V	( 5	25°C		34°								
φm	Phase margin	$V_{ } = 10 \text{ mV},$	$ V  = 10 \text{ mV},$ $ C_1  = 20 \text{ pF}$	$V_{l} = 10 \text{ mV},$ $C_{l} = 20 \text{ pF}$	$V_{\parallel} = 10 \text{ mV},$	$V_{l} = 10 \text{ mV},$ $C_{l} = 20 \text{ pF}$	V  = 10  mV,  C  = 20  pF,	V  = 10  mV, $ C_1  = 20 \text{ pF}$	f = B <sub>1</sub> , See Figure 3	−55°C		39°		
		- L - <b>- 2</b> p. ,	occ rigure o	125°C		25°								

## operating characteristics at specified free-air temperature, $V_{DD}$ = 10 V

PARAMETER		ETER TEST CONDITIONS		TA	TLC27L4M TLC27L9M			UNIT						
					MIN TYP MAX  0.05  0.06  0.03  0.04  0.06  0.03  70									
				25°C		0.05								
			V <sub>IPP</sub> = 1 V	−55°C		0.06								
SR	Clay rate at unity gain	$R_L = 1 M\Omega$ ,		125°C		0.03	3	\//uo						
J SK	Slew rate at unity gain	C <sub>L</sub> = 20 <b>p</b> F, See Figure 1		25°C		0.04		V/μs						
		g	3	V <sub>IPP</sub> = 5.5 V	−55°C		0.06							
				125°C		0.03								
Vn	Equivalent input noise voltage	f = 1 kHz, See Figure 2	$R_S = 20 \Omega$ ,	25°C		70		nV/√ <del>Hz</del>						
		laximum output-swing bandwidth $V_O = V_{OH}$ , $C_L = 20$ pF, $R_L = 1$ M $\Omega$ , See Figure		25°C		1								
ВОМ	Maximum output-swing bandwidth		C <sub>L</sub> = 20 pF, See Figure 1	−55°C		1.5	kHz							
		17( 1 10152,	occ rigure r	125°C		0.7								
				25°C		110								
В1	Unity-gain bandwidth	V <sub>I</sub> = 10 mV, See Figure 3	$C_L = 20 \text{ pF},$	−55°C		165		kHz						
		occ rigure 5		125°C		70								
		)/ <sub>1</sub> 40 m)/	4 D	25°C		38°								
φm	Phase margin	$V_{\parallel} = 10 \text{ mV},$	$V_{ } = 10 \text{ mV},$ $C_{ } = 20 \text{ pF}$	$V_1 = 10 \text{ mV},$ $C_1 = 20 \text{ pF}$	$V_{\parallel} = 10 \text{ mV},$ $C_{\parallel} = 20 \text{ pF},$	$V_{I} = 10 \text{ mV},$ $C_{I} = 20 \text{ pF}$	V  = 10  mV, $ C_1  = 20 \text{ pF}$	V  = 10  mV, $ C_1  = 20 \text{ pF}$	f = B <sub>1</sub> , See Figure 3	−55°C		43°		
			2229410 0	125°C		29°								

SLOS053C - OCTOBER 1987 - REVISED AUGUST 1994

## operating characteristics, $V_{DD}$ = 5 V, $T_A$ = 25°C

	PARAMETER		NDITIONS	TL	′	UNIT	
			NDITIONS	MIN	TYP	MAX	UNIT
		$R_L = 1 M\Omega$ , $C_L = 20 pF$ ,	V <sub>IPP</sub> = 1 V		0.03		V/μs
	Slew rate at unity gain		V <sub>IPP</sub> = 2.5 V		0.03		ν/μδ
٧n	Equivalent input noise voltage	f = 1 kHz, See Figure 2	$R_S = 20 \Omega$ ,		70		nV/√ <del>Hz</del>
ВОМ	Maximum output-swing bandwidth	$V_O = V_{OH},$ $R_L = 1 M\Omega,$	C <sub>L</sub> = 20 pF, See Figure 1		5		kHz
B <sub>1</sub>	Unity-gain bandwidth	V <sub>I</sub> = 10 mV, See Figure 3	C <sub>L</sub> = 20 pF,		85		kHz
фm	Phase margin	$V_I = 10 \text{ mV},$ $C_L = 20 \text{ pF},$	f = B <sub>1</sub> , See Figure 3		34°		

## operating characteristics, $V_{DD}$ = 10 V, $T_A$ = 25°C

	PARAMETER	TEST CO	TEST CONDITIONS			TLC27L4Y			
	PARAMETER	1231 001	MIN	TYP	MAX	UNIT			
SR	Slew rate at unity gain	$R_L = 1 M\Omega$ , $C_L = 20 pF$ ,	V <sub>IPP</sub> = 1 V		0.05		V/µs		
			V <sub>IPP</sub> = 5.5 V		0.04		ν/μδ		
Vn	Equivalent input noise voltage	f = 1 kHz, See Figure 2	$R_S = 20 \Omega$ ,		70		nV/√ <del>Hz</del>		
ВОМ	Maximum output-swing bandwidth	$V_O = V_{OH},$ $R_L = 1 M\Omega,$	C <sub>L</sub> = 20 pF, See Figure 1		1		kHz		
B <sub>1</sub>	Unity-gain bandwidth	V <sub>I</sub> = 10 mV, See Figure 3	C <sub>L</sub> = 20 pF,		110		kHz		
φm	Phase margin	$V_I = 10 \text{ mV},$ $C_L = 20 \text{ pF},$	$f = B_1$ , See Figure 3		38°	·	·		

#### PARAMETER MEASUREMENT INFORMATION

#### single-supply versus split-supply test circuits

Because the TLC27L4 and TLC27L9 are optimized for single-supply operation, circuit configurations used for the various tests often present some inconvenience since the input signal, in many cases, must be offset from ground. This inconvenience can be avoided by testing the device with split supplies and the output load tied to the negative rail. A comparison of single-supply versus split-supply test circuits is shown below. The use of either circuit gives the same result.

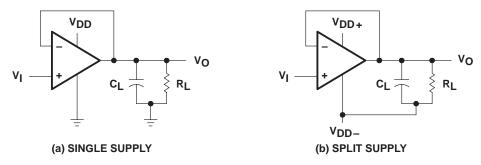


Figure 1. Unity-Gain Amplifier

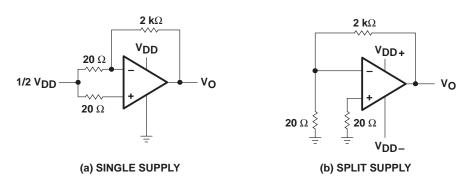


Figure 2. Noise-Test Circuit

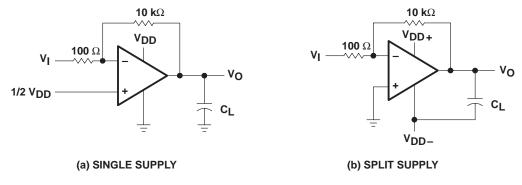


Figure 3. Gain-of-100 Inverting Amplifier



SLOS053C - OCTOBER 1987 - REVISED AUGUST 1994

#### PARAMETER MEASUREMENT INFORMATION

#### input bias current

Because of the high input impedance of the TLC27L4 and TLC27L9 operational amplifiers, attempts to measure the input bias current can result in erroneous readings. The bias current at normal room ambient temperature is typically less than 1 pA, a value that is easily exceeded by leakages on the test socket. Two suggestions are offered to avoid erroneous measurements:

- 1. Isolate the device from other potential leakage sources. Use a grounded shield around and between the device inputs (see Figure 4). Leakages that would otherwise flow to the inputs are shunted away.
- Compensate for the leakage of the test socket by actually performing an input bias current test (using a picoammeter) with no device in the test socket. The actual input bias current can then be calculated by subtracting the open-socket leakage readings from the readings obtained with a device in the test socket.

One word of caution: many automatic testers as well as some bench-top operational amplifier testers use the servo-loop technique with a resistor in series with the device input to measure the input bias current (the voltage drop across the series resistor is measured and the bias current is calculated). This method requires that a device be inserted into the test socket to obtain a correct reading; therefore, an open-socket reading is not feasible using this method.

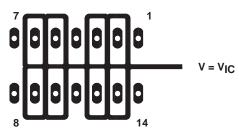


Figure 4. Isolation Metal Around Device Inputs (J and N packages)

#### low-level output voltage

To obtain low-supply-voltage operation, some compromise was necessary in the input stage. This compromise results in the device low-level output being dependent on both the common-mode input voltage level as well as the differential input voltage level. When attempting to correlate low-level output readings with those quoted in the electrical specifications, these two conditions should be observed. If conditions other than these are to be used, please refer to Figures 14 through 19 in the Typical Characteristics of this data sheet.

### input offset voltage temperature coefficient

Erroneous readings often result from attempts to measure temperature coefficient of input offset voltage. This parameter is actually a calculation using input offset voltage measurements obtained at two different temperatures. When one (or both) of the temperatures is below freezing, moisture can collect on both the device and the test socket. This moisture results in leakage and contact resistance, which can cause erroneous input offset voltage readings. The isolation techniques previously mentioned have no effect on the leakage since the moisture also covers the isolation metal itself, thereby rendering it useless. It is suggested that these measurements be performed at temperatures above freezing to minimize error.



SLOS053C - OCTOBER 1987 - REVISED AUGUST 1994

#### PARAMETER MEASUREMENT INFORMATION

#### full-power response

Full-power response, the frequency above which the operational amplifier slew rate limits the output voltage swing, is often specified two ways: full-linear response and full-peak response. The full-linear response is generally measured by monitoring the distortion level of the output while increasing the frequency of a sinusoidal input signal until the maximum frequency is found above which the output contains significant distortion. The full-peak response is defined as the maximum output frequency, without regard to distortion, above which full peak-to-peak output swing cannot be maintained.

Because there is no industry-wide accepted value for significant distortion, the full-peak response is specified in this data sheet and is measured using the circuit of Figure 1. The initial setup involves the use of a sinusoidal input to determine the maximum peak-to-peak output of the device (the amplitude of the sinusoidal wave is increased until clipping occurs). The sinusoidal wave is then replaced with a square wave of the same amplitude. The frequency is then increased until the maximum peak-to-peak output can no longer be maintained (Figure 5). A square wave is used to allow a more accurate determination of the point at which the maximum peak-to-peak output is reached.

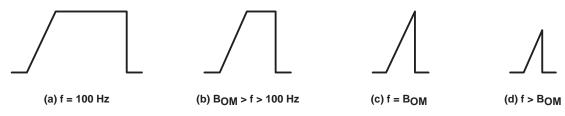


Figure 5. Full-Power-Response Output Signal

#### test time

Inadequate test time is a frequent problem, especially when testing CMOS devices in a high-volume, short-test-time environment. Internal capacitances are inherently higher in CMOS than in bipolar and BiFET devices and require longer test times than their bipolar and BiFET counterparts. The problem becomes more pronounced with reduced supply levels and lower temperatures.



SLOS053C - OCTOBER 1987 - REVISED AUGUST 1994

#### **TYPICAL CHARACTERISTICS**

#### **Table of Graphs**

			FIGURE
VIO	Input offset voltage	Distribution	6, 7
αVIO	Temperature coefficient	Distribution	8, 9
Vон	High-level output voltage	vs High-level output current vs Supply voltage vs Free-air temperature	10, 11 12 13
VOL	Low-level output voltage	vs Common-mode input voltage vs Differential input voltage vs Free-air temperature vs Low-level output current	14, 15 16 17 18, 19
AVD	Differential voltage amplification	vs Supply voltage vs Free-air temperature vs Frequency	20 21 32, 33
I <sub>IB</sub> /I <sub>IO</sub>	Input bias and input offset current	vs Free-air temperature	22
VIC	Common-mode input voltage	vs Supply voltage	23
IDD	Supply current	vs Supply voltage vs Free-air temperature	24 25
SR	Slew rate	vs Supply voltage vs Free-air temperature	26 27
	Normalized slew rate	vs Free-air temperature	28
VO(PP)	Maximum peak-to-peak output voltage	vs Frequency	29
B <sub>1</sub>	Unity-gain bandwidth	vs Free-air temperature vs Supply voltage	30 31
фm	ψ <sub>m</sub> Phase margin vs Supply voltage vs Free-air temperature vs Capacitive loads		34 35 36
V <sub>n</sub>	Equivalent input noise voltage	vs Frequency	37
ф	Phase shift	vs Frequency	32, 33

#### TYPICAL CHARACTERISTICS

## DISTRIBUTION OF TLC27L4

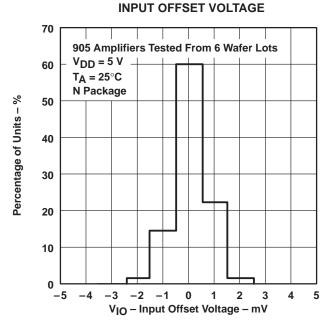


Figure 6

#### DISTRIBUTION OF TLC27L4 AND TLC27L9 INPUT OFFSET VOLTAGE TEMPERATURE COEFFICIENT

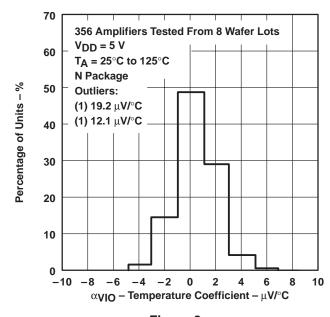


Figure 8

## DISTRIBUTION OF TLC27L4 INPUT OFFSET VOLTAGE

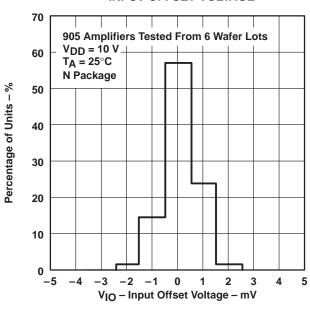


Figure 7

## DISTRIBUTION OF TLC27L4 AND TLC27L9 INPUT OFFSET VOLTAGE

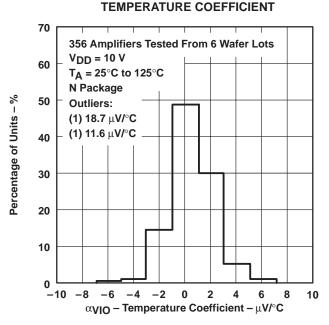


Figure 9

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#### TYPICAL CHARACTERISTICS<sup>†</sup>

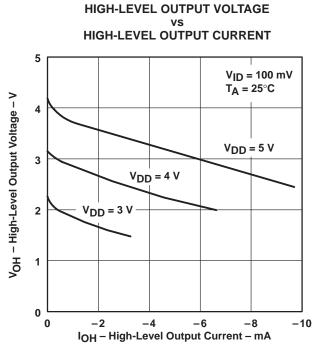
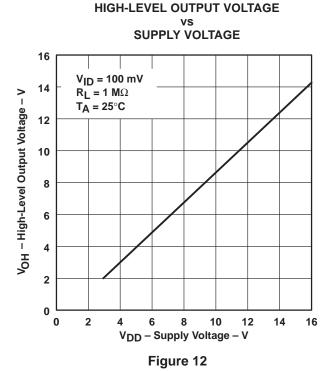


Figure 10



HIGH-LEVEL OUTPUT VOLTAGE HIGH-LEVEL OUTPUT CURRENT

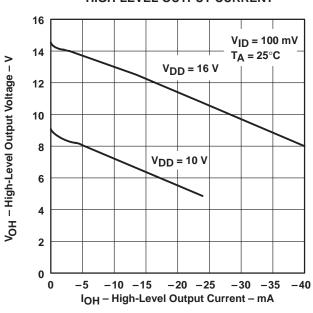
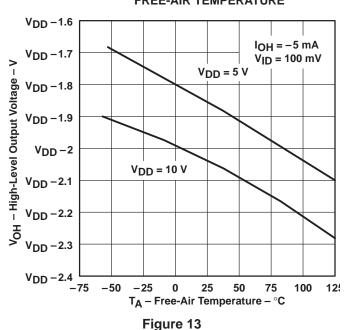
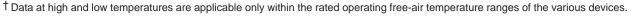


Figure 11

#### HIGH-LEVEL OUTPUT VOLTAGE VS FREE-AIR TEMPERATURE



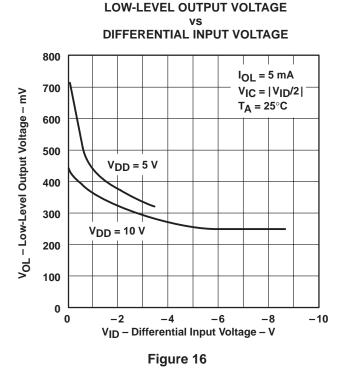




#### TYPICAL CHARACTERISTICS<sup>†</sup>

#### **LOW-LEVEL OUTPUT VOLTAGE COMMON-MODE INPUT VOLTAGE** 700 $V_{DD} = 5 V$ 650 $I_{OL} = 5 \text{ mA}$ V<sub>OL</sub> - Low-Level Output Voltage - mV T<sub>A</sub> = 25°C 600 550 $V_{ID} = -100 \text{ mV}$ 500 450 400 $V_{ID} = -1 V$ 350 300 0 1.5 2 2.5 3.5 V<sub>IC</sub> - Common-Mode Input Voltage - V

Figure 14



LOW-LEVEL OUTPUT VOLTAGE

VS

COMMON-MODE INPUT VOLTAGE

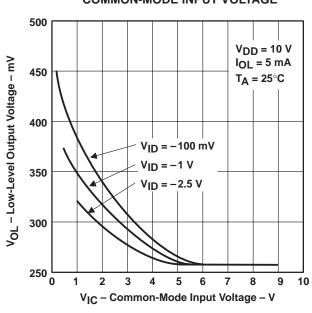


Figure 15

## LOW-LEVEL OUTPUT VOLTAGE vs FREE-AIR TEMPERATURE

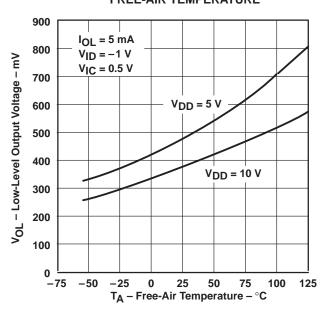


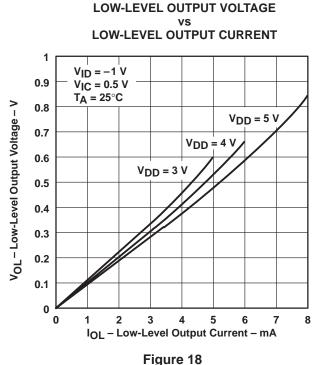
Figure 17

<sup>†</sup> Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.



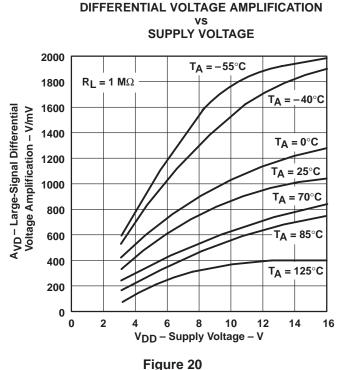
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#### TYPICAL CHARACTERISTICS<sup>†</sup>



riguic 10

LARGE-SIGNAL



LOW-LEVEL OUTPUT VOLTAGE
vs
LOW-LEVEL OUTPUT CURRENT

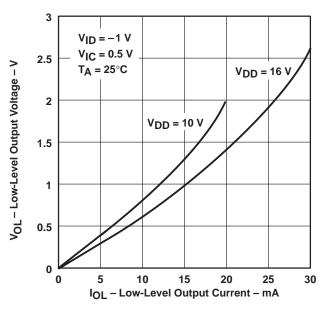


Figure 19

# LARGE-SIGNAL DIFFERENTIAL VOLTAGE AMPLIFICATION vs FREE-AIR TEMPERATURE

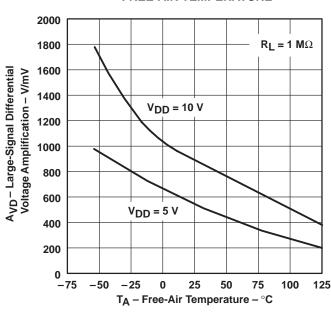


Figure 21

<sup>†</sup> Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.



#### TYPICAL CHARACTERISTICS<sup>†</sup>

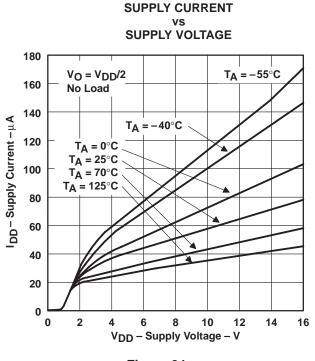
## INPUT BIAS CURRENT AND INPUT OFFSET CURRENT FREE-AIR TEMPERATURE

#### 10000 IIB and IIO - Input Bias and Offset Currents - pA $V_{DD} = 10 V$ **VIC = 5 V** See Note A 1000 $I_{IB}$ 100 lιο 10 1 0.1 25 45 65 85 105 125

NOTE A: The typical values of input bias current and input offset current below 5 pA were determined mathematically.

### Figure 22

T<sub>A</sub> – Free-Air Temperature – °C



### Figure 24

#### **COMMON-MODE INPUT VOLTAGE POSITIVE LIMIT** VS

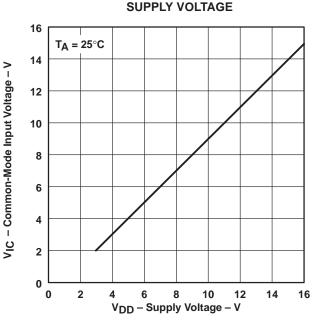
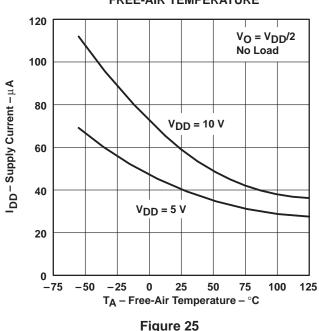


Figure 23

## **SUPPLY CURRENT** FREE-AIR TEMPERATURE



† Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.



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#### TYPICAL CHARACTERISTICS<sup>†</sup>

0.07

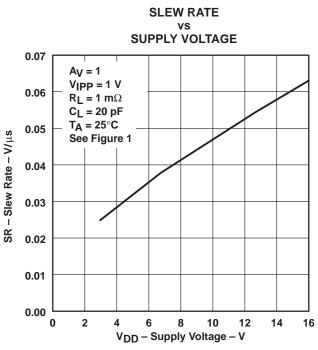
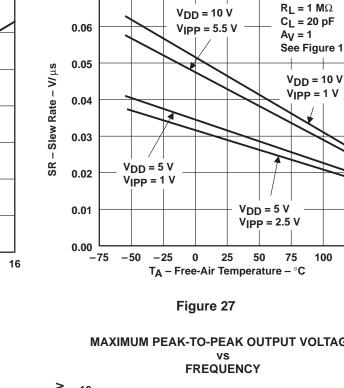
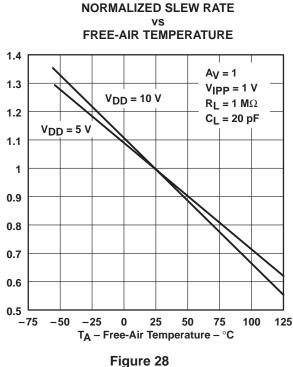


Figure 26





Normalized Slew Rate



100

125

**SLEW RATE** 

٧S FREE-AIR TEMPERATURE

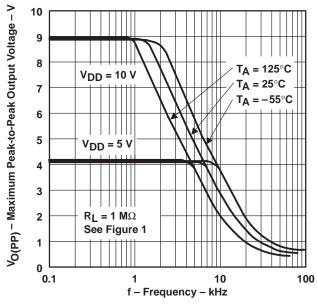
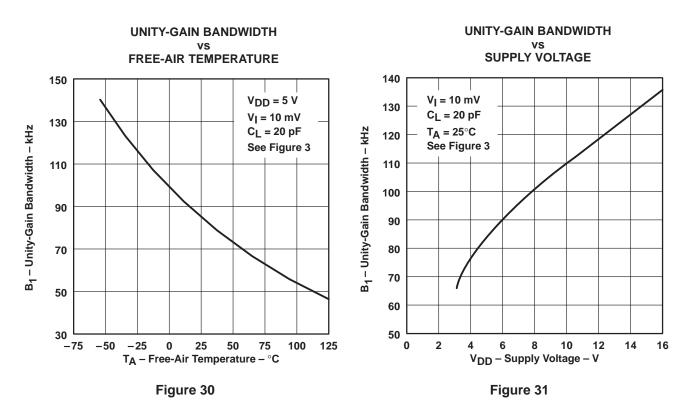


Figure 29

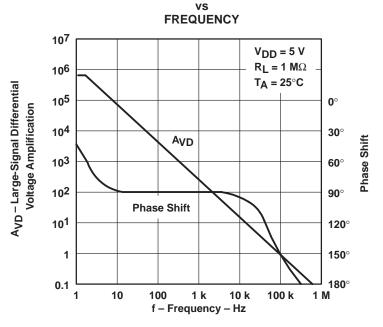
<sup>†</sup> Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.



#### TYPICAL CHARACTERISTICS<sup>†</sup>



## LARGE-SIGNAL DIFFERENTIAL VOLTAGE AMPLIFICATION AND PHASE SHIFT



<sup>†</sup> Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.



Figure 32

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#### TYPICAL CHARACTERISTICS<sup>†</sup>

## LARGE-SIGNAL DIFFERENTIAL VOLTAGE AMPLIFICATION AND PHASE SHIFT

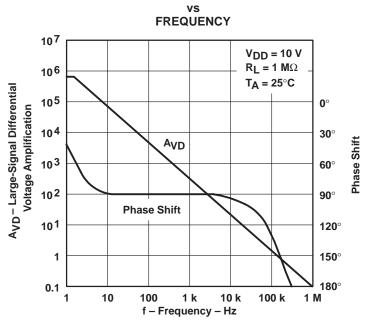
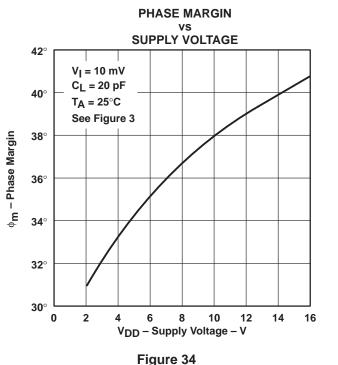


Figure 33



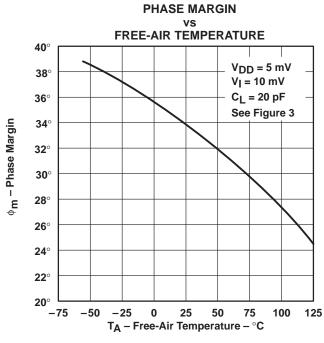


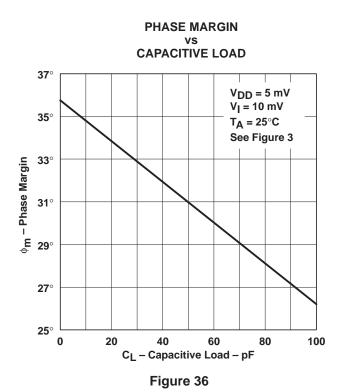
Figure 35

<sup>†</sup> Data at high and low temperatures are applicable only within the rated operating free-air temperature ranges of the various devices.



SLOS053C - OCTOBER 1987 - REVISED AUGUST 1994

#### **TYPICAL CHARACTERISTICS**



**EQUIVALENT INPUT NOISE VOLTAGE** vs FREQUENCY 200 V<sub>n</sub> − Equivalent Input Noise Voltage − nV/√Hz  $V_{DD} = 5 V$  $R_S = 20 \Omega$ 175 T<sub>A</sub> = 25°C See Figure 2 150 125 100 75 50 25 0 100 1000 f - Frequency - Hz

Figure 37

#### single-supply operation

While the TLC27L4 and TLC27L9 perform well using dual power supplies (also called balanced or split supplies), the design is optimized for single-supply operation. This design includes an input common-mode voltage range that encompasses ground as well as an output voltage range that pulls down to ground. The supply voltage range extends down to 3 V (C-suffix types), thus allowing operation with supply levels commonly available for TTL and HCMOS; however, for maximum dynamic range, 16-V single-supply operation is recommended.

Many single-supply applications require that a voltage be applied to one input to establish a reference level that is above ground. A resistive voltage divider is usually sufficient to establish this reference level (see Figure 38). The low input bias current of the TLC27L4 and TLC27L9 permits the use of very large resistive values to implement the voltage divider, thus minimizing power consumption.

The TLC27L4 and TLC27L9 work well in conjunction with digital logic; however, when powering both linear devices and digital logic from the same power supply, the following precautions are recommended:

- Power the linear devices from separate bypassed supply lines (see Figure 39); otherwise, the linear device supply rails can fluctuate due to voltage drops caused by high switching currents in the digital logic.
- 2. Use proper bypass techniques to reduce the probability of noise-induced errors. Single capacitive decoupling is often adequate; however, high-frequency applications may require RC decoupling.

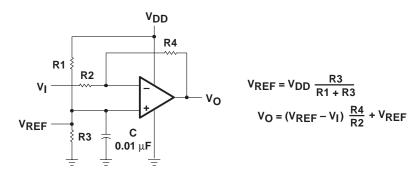


Figure 38. Inverting Amplifier With Voltage Reference



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#### APPLICATION INFORMATION

#### single-supply operation (continued)

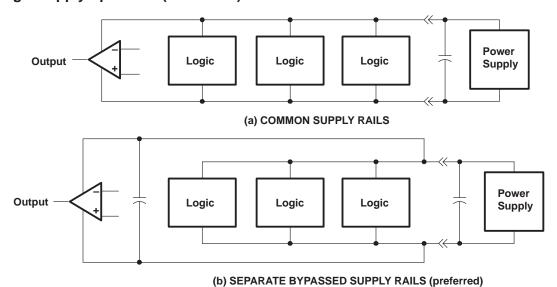


Figure 39. Common Versus Separate Supply Rails

#### input characteristics

The TLC27L4 and TLC27L9 are specified with a minimum and a maximum input voltage that, if exceeded at either input, could cause the device to malfunction. Exceeding this specified range is a common problem, especially in single-supply operation. Note that the lower range limit includes the negative rail, while the upper range limit is specified at  $V_{DD}-1$  V at  $T_A=25$ °C and at  $V_{DD}-1.5$  V at all other temperatures.

The use of the polysilicon-gate process and the careful input circuit design gives the TLC27L4 and TLC27L9 very good input offset voltage drift characteristics relative to conventional metal-gate processes. Offset voltage drift in CMOS devices is highly influenced by threshold voltage shifts caused by polarization of the phosphorus dopant implanted in the oxide. Placing the phosphorus dopant in a conductor (such as a polysilicon gate) alleviates the polarization problem, thus reducing threshold voltage shifts by more than an order of magnitude. The offset voltage drift with time has been calculated to be typically 0.1  $\mu$ V/month, including the first month of operation.

Because of the extremely high input impedance and resulting low bias current requirements, the TLC27L4 and TLC27L9 are well suited for low-level signal processing; however, leakage currents on printed circuit boards and sockets can easily exceed bias current requirements and cause a degradation in device performance. It is good practice to include guard rings around inputs (similar to those of Figure 4 in the Parameter Measurement Information section). These guards should be driven from a low-impedance source at the same voltage level as the common-mode input (see Figure 40).

The inputs of any unused amplifiers should be tied to ground to avoid possible oscillation.

#### noise performance

The noise specifications in operational amplifier circuits are greatly dependent on the current in the first-stage differential amplifier. The low input bias current requirements of the TLC27L4 and TLC27L9 result in a very low noise current, which is insignificant in most applications. This feature makes the devices especially favorable over bipolar devices when using values of circuit impedance greater than 50 k $\Omega$ , since bipolar devices exhibit greater noise currents.



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#### APPLICATION INFORMATION

#### noise performance (continued)

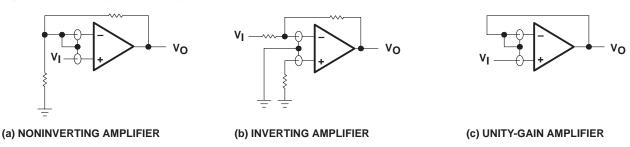


Figure 40. Guard-Ring Schemes

#### output characteristics

The output stage of the TLC27L4 and TLC27L9 is designed to sink and source relatively high amounts of current (see typical characteristics). If the output is subjected to a short-circuit condition, this high current capability can cause device damage under certain conditions. Output current capability increases with supply voltage.

All operating characteristics of the TLC27L4 and TLC27L9 were measured using a 20-pF load. The devices drive higher capacitive loads; however, as output load capacitance increases, the resulting response pole occurs at lower frequencies, thereby causing ringing, peaking, or even oscillation (see Figure 41). In many cases, adding a small amount of resistance in series with the load capacitance alleviates the problem.

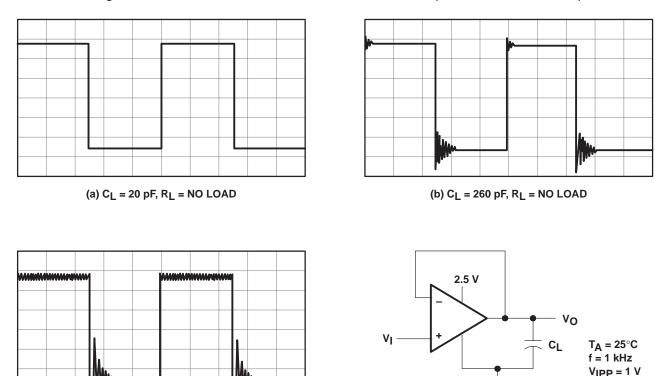


Figure 41. Effect of Capacitive Loads and Test Circuit

(c)  $C_L = 310 \text{ pF}, R_L = NO \text{ LOAD}$ 

-2.5 V

(d) TEST CIRCUIT

#### output characteristics (continued)

Although the TLC27L4 and TLC27L9 possess excellent high-level output voltage and current capability, methods for boosting this capability are available, if needed. The simplest method involves the use of a pullup resistor (Rb) connected from the output to the positive supply rail (see Figure 42). There are two disadvantages to the use of this circuit. First, the NMOS pulldown transistor N4 (see equivalent schematic) must sink a comparatively large amount of current. In this circuit, N4 behaves like a linear resistor with an on-resistance between approximately 60  $\Omega$  and 180  $\Omega$ , depending on how hard the operational amplifier input is driven. With very low values of R<sub>P</sub>, a voltage offset from 0 V at the output occurs. Second, pullup resistor R<sub>P</sub> acts as a drain load to N4 and the gain of the operational amplifier is reduced at output voltage levels where N5 is not supplying the output current.

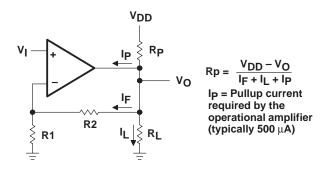


Figure 42. Resistive Pullup to Increase VOH

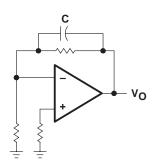


Figure 43. Compensation for Input Capacitance

#### feedback

Operational amplifier circuits nearly always employ feedback, and since feedback is the first prerequisite for oscillation, some caution is appropriate. Most oscillation problems result from driving capacitive loads (discussed previously) and ignoring stray input capacitance. A small-value capacitor connected in parallel with the feedback resistor is an effective remedy (see Figure 43). The value of this capacitor is optimized empirically.

#### electrostatic discharge protection

The TLC27L4 and TLC27L9 incorporate an internal electrostatic discharge (ESD) protection circuit that prevents functional failures at voltages up to 2000 V as tested under MIL-STD-883C, Method 3015.2. Care should be exercised, however, when handling these devices, as exposure to ESD may result in the degradation of the device parametric performance. The protection circuit also causes the input bias currents to be temperature dependent and have the characteristics of a reverse-biased diode.

#### latch-up

Because CMOS devices are susceptible to latch-up due to their inherent parasitic thyristors, the TLC27L4 and TLC27L9 inputs and outputs were designed to withstand -100-mA surge currents without sustaining latch-up; however, techniques should be used to reduce the chance of latch-up whenever possible. Internal protection diodes should not, by design, be forward biased. Applied input and output voltage should not exceed the supply voltage by more than 300 mV. Care should be exercised when using capacitive coupling on pulse generators. Supply transients should be shunted by the use of decoupling capacitors (0.1  $\mu$ F typical) located across the supply rails as close to the device as possible.



#### latch-up (continued)

The current path established if latch-up occurs is usually between the positive supply rail and ground and can be triggered by surges on the supply lines and/or voltages on either the output or inputs that exceed the supply voltage. Once latch-up occurs, the current flow is limited only by the impedance of the power supply and the forward resistance of the parasitic thyristor and usually results in the destruction of the device. The chance of latch-up occurring increases with increasing temperature and supply voltages.

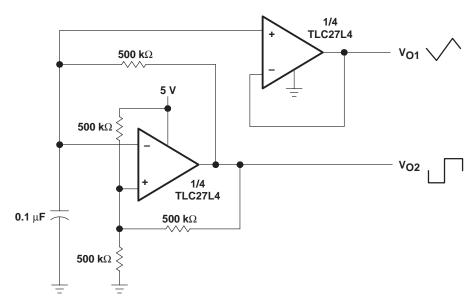
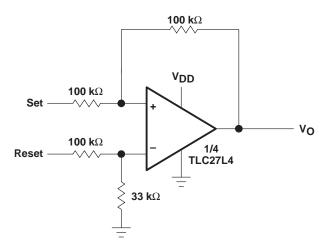


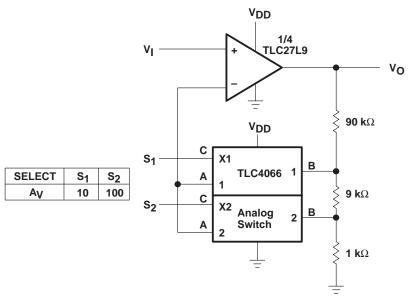
Figure 44. Multivibrator



NOTE:  $V_{DD} = 5 \text{ V to } 16 \text{ V}$ 

Figure 45. Set/Reset Flip-Flop





NOTE:  $V_{DD} = 5 \text{ V}$  to 12 V

Figure 46. Amplifier With Digital Gain Selection

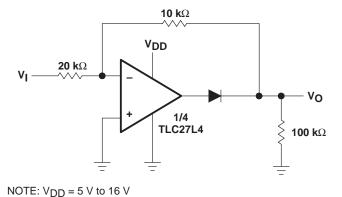
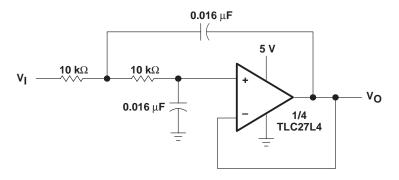


Figure 47. Full-Wave Rectifier

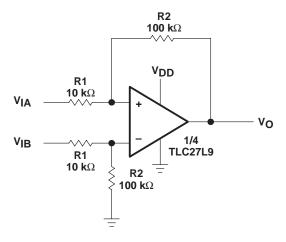
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#### **APPLICATION INFORMATION**



NOTE: Normalized to FC = 1 kHz and RL = 10 k $\Omega$ 

Figure 48. Two-Pole Low-Pass Butterworth Filter



NOTE:  $V_{DD} = 5 \text{ V to } 16 \text{ V}$  $V_{O} = \frac{R2}{R1} (V_{IB} - V_{IA})$ 

Figure 49. Difference Amplifier

#### **IMPORTANT NOTICE**

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